

(12) PATENT APPLICATION PUBLICATION

(21) Application  
No.201911043717 A

(19) INDIA

(22) Date of filing of Application :28/10/2019

(43) Publication Date :  
29/11/2019

(54) Title of the invention : DEVICE FOR SURFACE ROUGHNESS MEASUREMENT OF AN OBJECT

(51)  
International :H04N0005232000,G01B0011300000,A61B0001045000,B64C0039020000,G08G0001160000  
classification  
(31) Priority  
Document :NA  
No  
(32) Priority :NA  
Date  
(33) Name  
of priority :NA  
country  
(86)  
International  
Application :NA  
No :NA  
Filing  
Date  
(87)  
International : NA  
Publication  
No  
(61) Patent  
of Addition  
to  
Application :NA  
Number :NA  
Filing  
Date  
(62)  
Divisional to  
Application :NA  
Number :NA  
Filing  
Date

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(57) Abstract :

The present disclosure relates to a device for surface roughness measurement of an object, said device includes a camera for capturing one or more images of the object, and a control unit operatively coupled with the camera. The control unit comprises a processor coupled to a memory, the memory storing instructions executable by the processor to receive the captured one or more images from the camera and define a Region of Interest (ROI) for each the captured one or more images, wherein the ROI is defined based on geometrical section of each of the captured one or more images, determine surface roughness in the ROI by analysing gradient value of edges for each of the captured one or more images, wherein the surface roughness is analysed based on averaging of ROI over a span of the captured one or more images.

No. of Pages : 24 No. of Claims : 10